## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10590632	JENSEN ET AL.
Examiner	Art Unit
Young J Kim	1637

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES				
Search Notes	Date	Examiner		
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	9/15/2008	/YJK/		
see enclosed for text-search strategy	9/15/2008	/YJK/		
updated - patent databases search - see enclosed for text-search strategy	5/13/2009	/YJK/		
updated - patent databases search - see enclosed for text-search strategy	3/9/2010	/YJK/		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
	Interference search - see enclosed for search strategy	3/9/2010	/YJK/	

	/Young J Kim/ Primary Examiner.Art Unit 1637
--	---

U.S. Patent and Trademark Office Part of Paper No. : 20100304